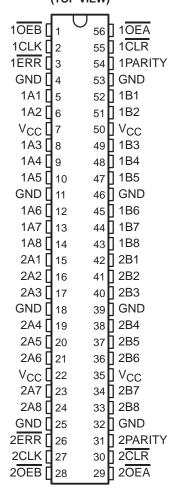
- Members of the Texas Instruments Widebus™ Family
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce)
 1 V at V_{CC} = 5 V, T_A = 25°C
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OI})
- Parity-Error Flag With Parity Generator/Checker
- Register for Storage of Parity-Error Flag
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

The 'ABT16833 consist of two noninverting 8-bit to 9-bit parity bus transceivers and are designed for communication between data buses. For each transceiver, when data is transmitted from the A bus to the B bus, an odd-parity bit is generated and output on the parity I/O pin (1PARITY or 2PARITY). When data is transmitted from the B bus to the A bus, 1PARITY (or 2PARITY) is configured as an input and combined with the B-input data to generate an active-low error flag if odd parity is not detected.

SN54ABT16833 . . . WD PACKAGE SN74ABT16833 . . . DGG OR DL PACKAGE (TOP VIEW)



The error (1ERR or 2ERR) output is configured as an open-collector output. The B-to-A parity-error flag is clocked into 1ERR (or 2ERR) on the low-to-high transition of the clock (1CLK or 2CLK) input. 1ERR (or 2ERR) is cleared (set high) by taking the clear (1CLR or 2CLR) input low.

The output-enable (OEA and OEB) inputs can be used to disable the device so that the buses are effectively isolated. When both OEA and OEB are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.



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description (continued)

The SN54ABT16833 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ABT16833 is characterized for operation from -40° C to 85° C.

FUNCTION TABLE

		I	NPUTS				OUTPU	JT AND I/O			
OEB	OEA	CLR	CLK	Ai Σ OF H	Bi [†] Σ OF H	Α	В	PARITY	ERR‡	FUNCTION	
L	Н	Х	Х	Odd Even	NA	NA	Α	L H	NA	A data to B bus and generate parity	
Н		Н	1	NA	Odd	В	NA	NA	Н	B data to A bus and	
_ ''			'	Even		14/4	L	check parity			
Х	Χ	L	Χ	Χ	Χ	Χ	NA	NA	Н	Check error-flag register	
		Н	No↑	Χ					NC		
н	Н	L No↑ X	Z	Н	2						
"	П	Н	\uparrow	Odd	Х	Z	Z	۷	Н	Isolation§	
		Н	\uparrow	Even					L		
		Х	Х	Odd	NA	NA	A	Н	NA	A data to B bus and	
-	L	^	^	Even	INA	INA	А	L	INA	generate inverted parity	

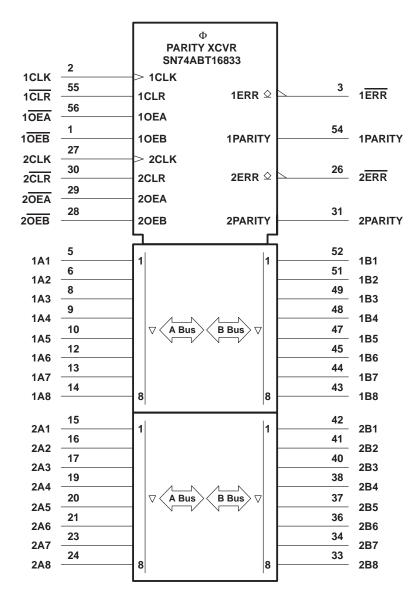
NA = not applicable, NC = no change, X = don't care

[†]Summation of high-level inputs includes PARITY along with Bi inputs.

[‡]Output states shown assume ERR was previously high.

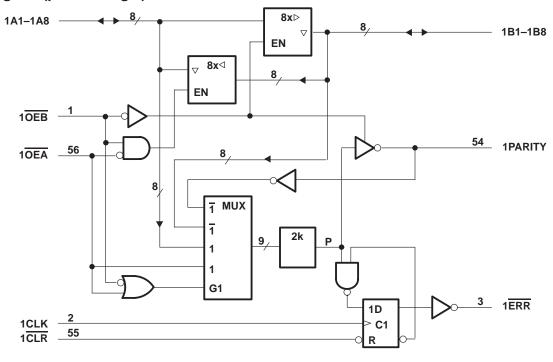
[§] In this mode, ERR (when clocked) shows inverted parity of the A bus.

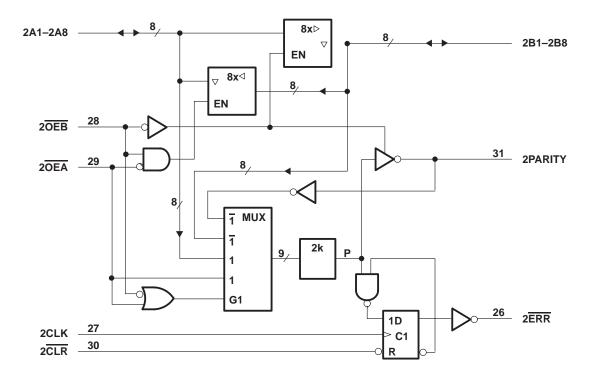
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



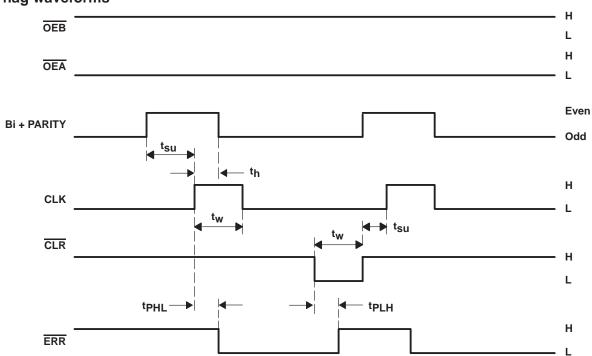


ERROR-FLAG FUNCTION TABLE

INP	UTS	INTERNAL TO DEVICE	OUTPUT PRE-STATE	OUTPUT ERR	FUNCTION		
CLR	CLK	POINT P	ERR _{n-1} †	EKK			
Н	1	Н	Н	Н			
Н	\uparrow	X	L	L	Sample		
Н	1	L	Χ	L			
L	Х	Х	Х	Н	Clear		

[†] State of ERR before changes at CLR, CLK, or point P

error-flag waveforms





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (except I/O ports) (see Note 1)	0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, VO	–0.5 V to 5.5 V
Current into any output in the low state, IO: SN54ABT16833	96 mA
SN74ABT16833	128 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ _{JA} (see Note 2): DGG package	81°C/W
DL package	
Storage temperature range, T _{Sto}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

					SN74ABT	UNIT	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	High-level input voltage		2	3	2		V
VIL	Low-level input voltage			0.8		0.8	V
VI	Input voltage		0	Vcc	0	VCC	V
Vон	High-level output voltage	ERR	7.4,	5.5		5.5	V
loh	High-level output current	Except ERR	27/	-24		-32	mA
l _{OL}	Low-level output current		70,	48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled	Q	10		10	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CON	T _A = 25°C			SN54ABT16833		SN74ABT16833		UNIT		
PAI	RAMETER	TEST CON	IDITIONS	MIN	TYP [†]	MAX	MIN	MAX	MIN	MAX	UNII	
VIK		$V_{CC} = 4.5 \text{ V},$	I _I = -18 mA			-1.2		-1.2		-1.2	V	
		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5	3		2.5				٧	
\/~	All outputs	$V_{CC} = 5 V$,	$I_{OH} = -3 \text{ mA}$	3	3.4		3		3			
VOH	except ERR	V _{CC} = 4.5 V	I _{OH} = -24 mA				2				v	
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*	2.7				2			
V/01		V _{CC} = 4.5 V	I _{OL} = 24 mA		0.25	0.55		0.55			V	
VOL		VCC = 4.5 V	I _{OL} = 64 mA		0.3	0.55*				0.55	V	
V _{hys}					100						mV	
IOH	ERR	$V_{CC} = 4.5 \text{ V},$	V _{OH} = 5.5 V			20		20		20	μΑ	
I _{off}		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100	4			±100	μΑ	
ICEX	Outputs high	$V_{CC} = 5.5 \text{ V},$	V _O = 5.5 V			50	9,	50		50	μΑ	
1.	Control inputs	Vcc = 5.5 V, V _I = V	an or CND			±1	35	±1		±1	μΑ	
1	A or B ports	vCC = 5.5 v, v = v	CC or GMD			±100	90	±100		±100	μА	
IJL	A or B ports	$V_{CC} = 0$,	$V_I = GND$			-50	t'a	- 50		-50	μΑ	
lo [‡]		$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V	-50	-100	-180	-50	-180	-50	-180	mA	
I _{OZH} §		V _{CC} =5.5 V,	$V_0 = 2.7 \text{ V}$			50		50		50	μΑ	
lozL§		V _{CC} = 5.5 V,	V _O = 0.5 V			-50		- 50		-50	μΑ	
		VCC = 5.5 V,	Outputs high		1.5	2		2		2		
Icc	A or B ports	$I_O = 0$,	Outputs low		28	36		36		36	mA	
		$V_I = V_{CC}$ or GND	Outputs disabled		1	2		2		2		
ΔICC¶		V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND				50		50		50	μА	
Ci	Control inputs	V _I = 2.5 V or 0.5 V			3						pF	
C _{io}	A or B ports	V _O = 2.5 V or 0.5 V			9						pF	

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.

[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 $[\]S$ The parameters $I_{\mbox{\scriptsize OZH}}$ and $I_{\mbox{\scriptsize OZL}}$ include the input leakage current.

[¶] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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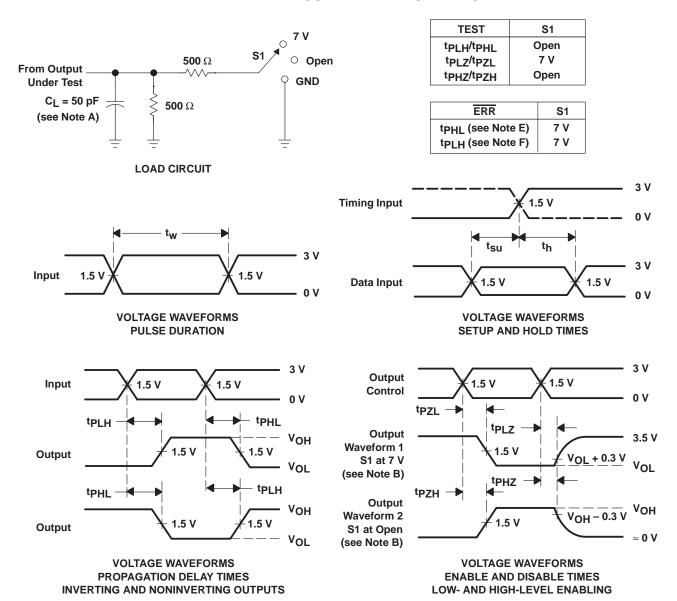
timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		V _{CC} = T _A = 2	: 5 V, 25°C	SN54ABT16833		SN74ABT16833		UNIT		
			MIN	MAX	MIN	MAX	MIN	MAX		
t _W	Pulse duration, CLK high or low		3		3_		3		ns	
		A port	4.5		4.5	2	4.5			
t _{su}	Setup time before CLK↑	CLR	1		813	4	1		ns	
		OEA	5		5		5			
t _h	Hold time after CLK↑	A port or OEA	0		0		0		ns	

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			SN54ABT16833		SN74ABT16833		UNIT	
	(INFOT)	(001F01)	MIN	TYP	MAX MIN MAX		MAX	MIN	MAX		
^t PLH	A or B	B or A	1.5	2.5	3.3	1.5	4.2	1.5	4.1	ns	
^t PHL	AUIB	B or A	2	3.1	3.9	2	4.5	2	4.3	115	
^t PZH	ŌĒ	A or B	2	3.9	4.9	2	5.8	2	5.6	no	
^t PZL		AUIB	2.5	4.3	5.1	2.5	6.2	2.5	6	ns	
^t PHZ	ŌĒ	A or B	2	3.6	4.5	2	5.5	2	5.4	ns	
t _{PLZ}			1.5	3	3.8	1.5	4.7	1.5	4.3		
^t PLH	. =	PARITY	2	4.6	5.4	2/	. 7	2	6.7	ns	
^t PHL	A or OE		2	4.3	5.1	2	6.5	2	6.1		
^t PZH	<u></u>	PARITY	2	3.6	5	0 2	5.8	2	5.7	ns	
^t PZL	ŌĒ	FARITI	2.5	4.4	5.8	2.5	6.7	2.5	6.5	115	
^t PHZ	ŌĒ	DADITY	1.5	3.2	4	1.5	4.8	1.5	4.7		
tPLZ		PARITY	1.5	2.9	3.7	1.5	4.2	1.5	4.1	ns	
t _{PLH}	CLK, CLR	<u></u>	2	3.4	4.2	2	4.8	2	4.6	ns	
tPHL	CLK	ERR	2	2.8	3.6	2	4.1	2	3.9	115	

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpHL is measured at 1.5 V.
- F. tpLH is measured at VOL + 0.3 V.

Figure 1. Load Circuit and Voltage Waveforms



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